

# Tuning the electrical transport of WS<sub>2</sub> by V substitution

---

## Van Dam Do

Van Tu Vu, Thanh Luan Phan, Thi Thanh Huong Vu, Woo Jong Yu\*

*Department of Electrical and Computer Engineering, Sungkyunkwan University, Suwon, Korea.*

Contact@E-mail: [dodamdvd@skku.edu](mailto:dodamdvd@skku.edu), [micco21@skku.edu](mailto:micco21@skku.edu)

---

## Abstract

Substitutional doping of two-dimensional transition metal dichalcogenides (2D-TMDs) has been proven to be effective way to modify the electronic properties for their applications in electronic and photonic engineering. However, control of p-type conductivity in tungsten disulfide (WS<sub>2</sub>) remains challenging. Herein, we report controllable growth of vanadium (V) doping monolayer WS<sub>2</sub> with various doping concentrations by mixing of a tungsten source and vanadium dopant. The atomic-resolution scanning transmission electron microscopy (STEM), photoluminescence spectroscopy (PL), Raman spectroscopy, X-ray photoelectron spectroscopy (XPS) evidence the V substitution doping in the WS<sub>2</sub> lattice. The V-doped WS<sub>2</sub> FET shows a transformation from n-type at 0%V to ambipolar (10%V), p-type (20%V) and degenerate (30%). A vertical p-n homojunction based on pure WS<sub>2</sub> and V-doped WS<sub>2</sub> shows a good rectification ratio. This work will can be extended for controllable doping in other TMDs materials for further electronic and optoelectronic applications.

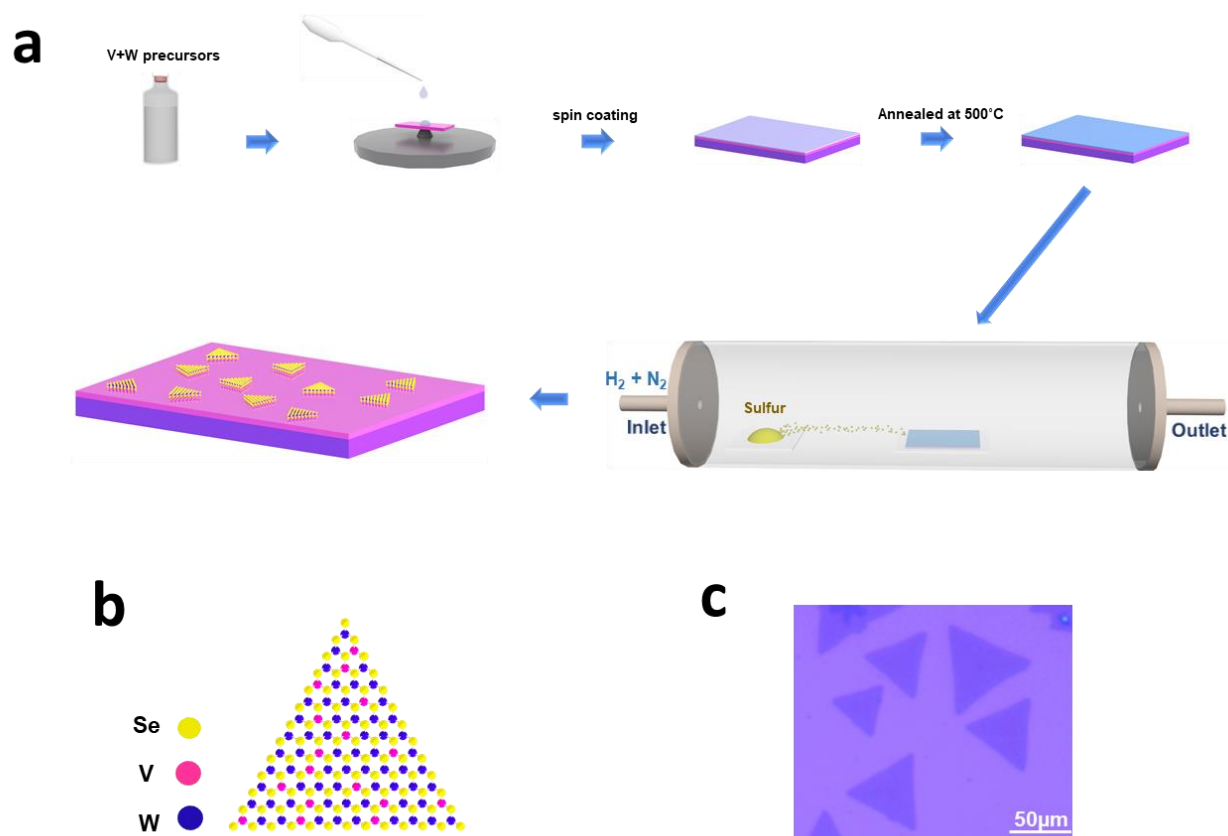


Figure 1: Growth of V-doped WS<sub>2</sub>

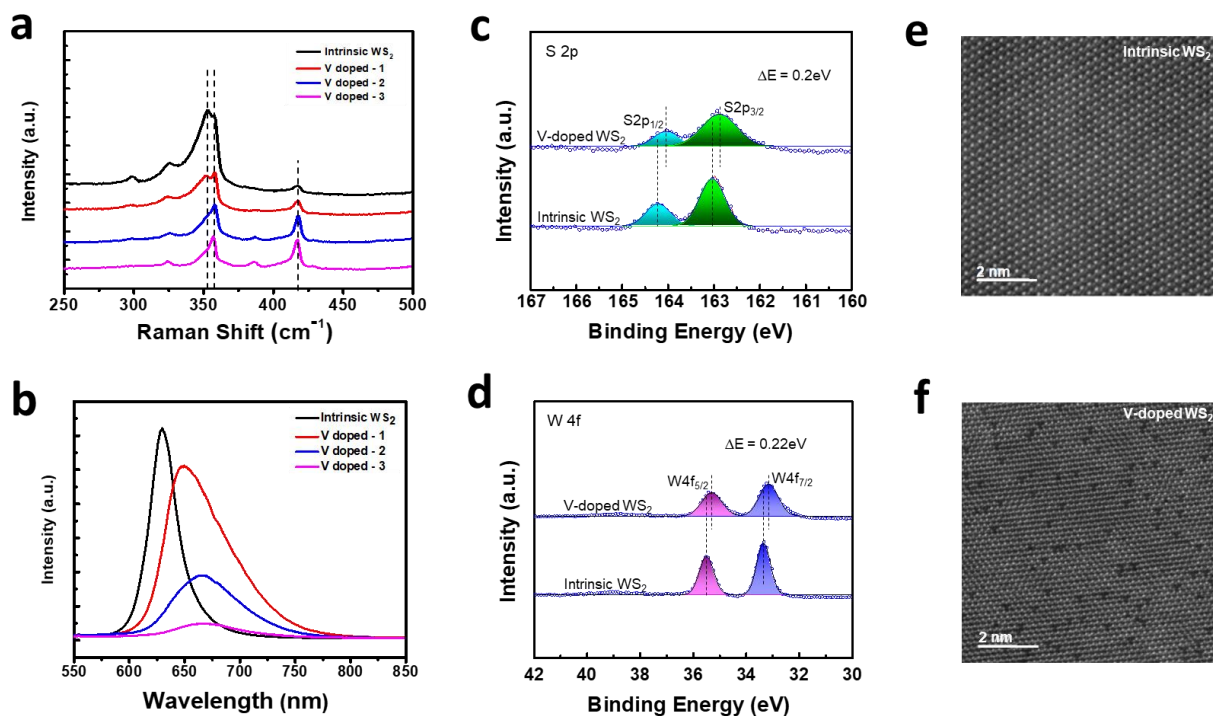


Figure 2: (a, b) Raman and PL spectra of undoped and doped monolayer WS<sub>2</sub> with different V percent, respectively. XPS scans of (c) S 2p and (d) W 4f core-level binding energies for intrinsic and doped monolayer WS<sub>2</sub>. (e, f) HAADF-STEM images of undoped and doped monolayer WS<sub>2</sub>. Scale bars are 2nm.